Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/837,222	LIN, WEI	
Examiner	Art Unit	
Tri H. Phan	2616	

SEARCHED				
Class	Subclass	Date	Examiner	
370	229- 238,395.2- 395.4	4/18/2006	TP	
370	465-469	4/18/2006	TP	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
1	ce search printout	4/18/2006	TP	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST (USPT, JPAB, EPAB, DWPI) - see search history printout	4/18/2006	TP		
370/229-238,395.2,395.4 (seetext search only history printout)	4/18/2006	TP		
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